

C.14 Microprocessor Verification and Test

- M. S. Abadir, editor, *Special Issue on Microprocessor Test and Verification*, volume 16, number 1/2 of *Journal of Electronic Testing: Theory and Applications*. Boston: Kluwer Academic Publishers, February/April 2000.

C.15 Semiconductor Defect Mechanisms

- E. A. Amerasekera and D. S. Campbell, *Failure Mechanisms in Semiconductor Devices*. Chichester, United Kingdom: John Wiley & Sons, 1987.
- S. Dabral and T. J. Maloney, *Basic ESD and I/O Design*. New York: John Wiley & Sons, 1998.
- J. P. deGvez and D. K. Pradhan, *Integrated Circuit Manufacturability*. Piscataway, New Jersey: IEEE Press, 1998.
- S. W. Director, W. Maly, and A. J. Strojwas, *VLSI Design for Manufacturing Yield Enhancement*. Boston: Kluwer Academic Publishers, 1989.
- A. P. Dorey, B. K. Jones, A. M. D. Richardson, and Y. Z. Xu, *Rapid Reliability Assessment of VLSI*, Boston: Plenum Publishers/Kluwer Academic Press, 1990.
- W. D. Greason, *Electrostatic Damage in Electronics*. Somerset, New Jersey: Wiley, 1987.
- M. J. Howes and D. V. Morgan, editors, *Reliability and Degradation – Semiconductor Devices and Circuits*. Chichester, United Kingdom: Wiley-Interscience, 1981.
- J. B. Khare and W. Maly, *From Contamination to Defects, Faults and Yield Loss: Simulation and Applications*. Boston: Kluwer Academic Publishers, 1996.
- D. J. Klinger, Y. Nakada, and M. A. Manendez, *AT&T Reliability Manual*. Florence, Kentucky: Van Nostrand Reinhold, 1990.
- J. M. Kolyer and D. E. Watson, *ESD A to Z Electrostatic Discharge Control for Electronics*. New York: Van Nostrand Reinhold, 1990.
- M. Sachdev, *Defect Oriented Testing for CMOS Analog and Digital Circuits*. Boston: Kluwer Academic Publishers, 1998.

C.16 System Test

- K. Chakrabarty, V. Iyengar, and A. Chandra, *Test Resource Partitioning for System-on-a-Chip*. Boston: Kluwer Academic Publishers, 2002.
- R. Rajsuman, *System-on-a-Chip: Design and Test*. Boston: Artech House, 2000.
- J. W. Sheppard and W. R. Simpson, *Research Perspectives and Case Studies in System Test and Diagnosis*. Boston: Kluwer Academic Publishers, 1998.
- W. R. Simpson and J. W. Sheppard, *System Test and Diagnosis*. Boston: Kluwer Academic Publishers, 1994.

C.17 Test Economics

- M. Abadir and A. P. Ambler, editors, *Economics of Electronic Design, Manufacture and Test*. Boston: Kluwer Academic Publishers, 1994.
- A. P. Ambler, M. Abadir, and S. Sastry, editors, *Economics of Design and Test for Electronics Circuits and Systems*. Chichester, United Kingdom: Ellis Horwood, 1992.
- B. Davis, *The Economics of Automatic Testing*. London, United Kingdom: McGraw-Hill, 1982.